Am29203

## Four-Bit Bipolar Microprocessor Slice

DISTINCTIVE CHARACTERISTICS

- **Expandable Register File**
  The Am29203 includes the necessary "hooks" to expand the register file externally to any number of registers.
- **Built-in Multiplication Logic**
  Performing multiplication with the Am2901A requires a few external gates — these gates are contained on-chip in the Am29203. Three special instructions are used for unsigned multiplication, two's-complement multiplication, and the last cycle of a two's-complement multiplication.
- **Built-in Division Logic**
  The Am29203 contains all logic and interconnects for execution of a non-restoring, multiple-length division with correction of the quotient.

- **Built-in Normalization Logic**
  The mantissa and exponent of a floating-point number can be developed using a single microcycle per shift.
- **Built-in Parity Generation and Sign Extension Circuitry**
  Can supply parity across the entire ALU outputs and provide sign-extension at any slice boundary.
- **BCD Arithmetic**
  The Am29203 features automatic BCD add and subtract, and conversion between binary and BCD.
- **Two Bidirectional Data Lines**
- **Improved I/O Capability**
  Both the DA and DB data buses are bidirectional on the Am29203. In addition, the Y port is also bidirectional.

GENERAL DESCRIPTION

The Am29203 is a four-bit expandable bipolar microprocessor slice. The Am29203 performs all functions performed by the industry standard Am2901 and Am2903A, and in addition, provides a number of significant enhancements that are especially useful in arithmetic-oriented processors. Infinitely expandable memory and three-port, three-address architecture are provided by the Am29203. In addition to its complete arithmetic and logic instruction set, the Am29203 provides a special set of instructions that facilitates the implementation of multiplication, division, normalization, BCD arithmetic and conversion, and other previously time-consuming operations. The Am29203 has three bidirectional ports and features AMD's ion-implanted micro-oxide (IMOX[TM]) technology.

BLOCK DIAGRAM
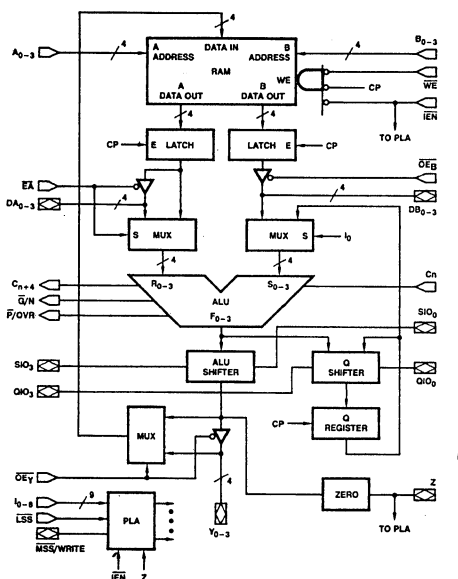
BD002786

RELATED PRODUCTS

Part No.	Description
Am2902A	Carry Look-Ahead Generator
Am2904	Status and Shift Control Unit
Am2910A	Microprogram Controller
Am2914	Vectored Priority Interrupt Controller
Am2918	Pipeline Register
Am2920	Octal Register
Am2922	Condition Code MUX
Am2925	System Clock Generator
Am2940	DMA Address Generator
Am2952	Bidirectional I/O Port
Am29707	Two-Port RAM
Am27S35	Registered PROM

CONNECTION DIAGRAMS
Top View

DIP*
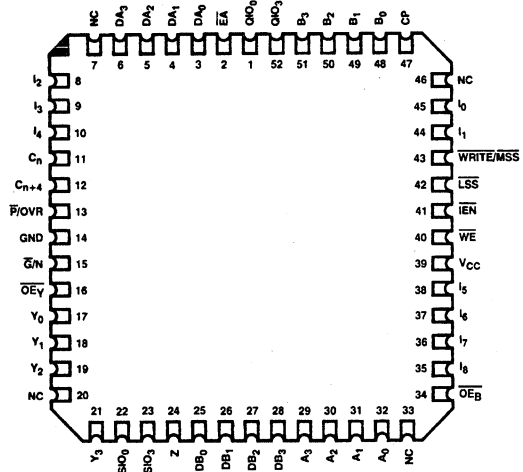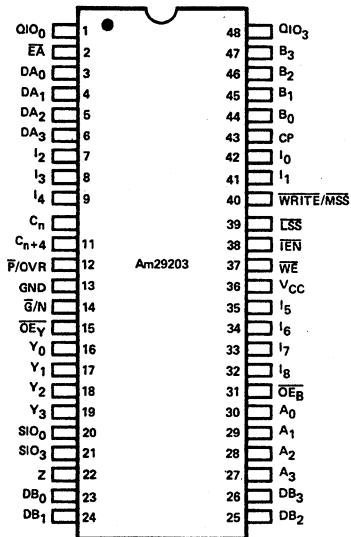
CD004882

CD004502

*Also available in 48-Pin Ceramic Flatpack. Connections identical to DIP.

Note: Pin 1 is marked for orientation.

LOGIC SYMBOL

LS002281

V_{CC} = Power Supply
GND = Ground

METALLIZATION AND PAD LAYOUT
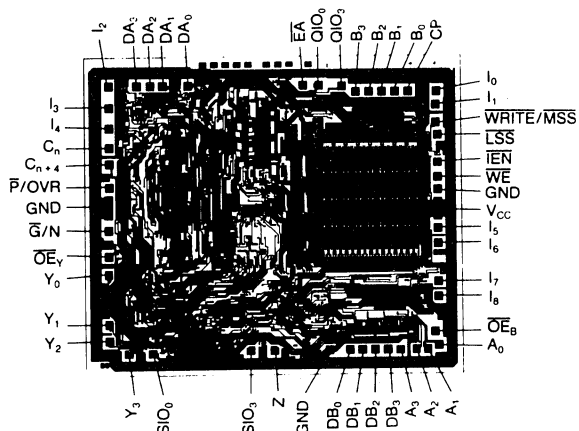
DIE SIZE 0.163″ x 0.197″

ORDERING INFORMATION

Standard Products

AMD standard products are available in several packages and operating ranges. The order number (Valid Combination) is formed by a combination of: **A. Device Number**
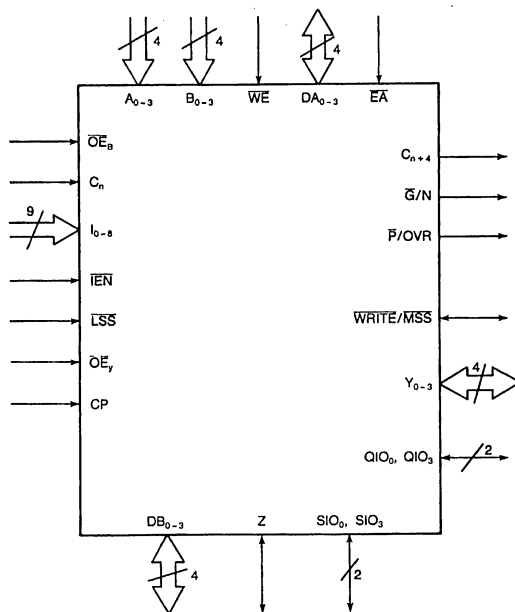**B. Speed Option** (if applicable)
C. Package Type
D. Temperature Range
E. Optional Processing

AM29203   D   C   B

E. OPTIONAL PROCESSING
Blank = Standard Processing
B = Burn-in

D. TEMPERATURE RANGE
C = Commercial (0 to +70°C)

C. PACKAGE TYPE
D = 48-Pin Sidebrazed Hermetic Ceramic DIP
(SD 048)

B. SPEED OPTION
Not Applicable

A. DEVICE NUMBER/DESCRIPTION
Am29203
Four-Bit Bipolar Microprocessor Slice
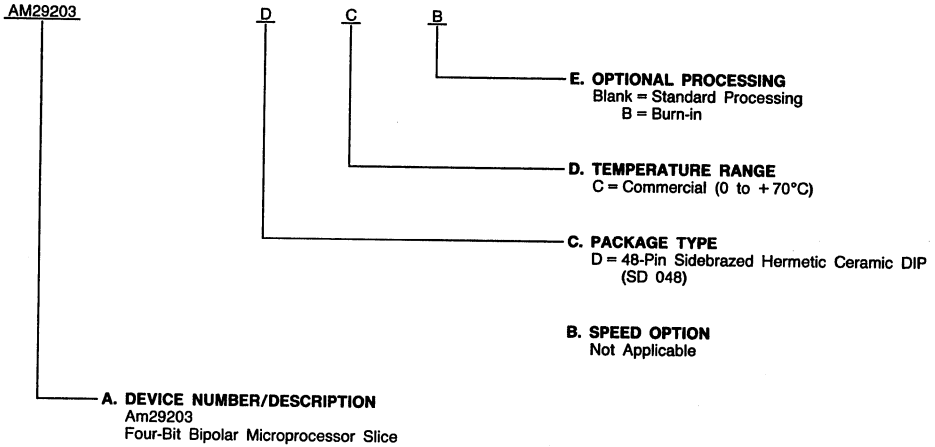
Valid Combinations	
AM29203	DC, DCB

Valid Combinations

Valid Combinations list configurations planned to be supported in volume for this device. Consult the local AMD sales office to confirm availability of specific valid combinations, to check on newly released combinations, and to obtain additional data on AMD's standard military grade products.

ORDERING INFORMATION

APL and CPL Products

AMD products for Aerospace and Defense applications are available in several packages and operating ranges. APL (Approved Products List) products are fully compliant with MIL-STD-883C requirements. CPL (Controlled Products List) products are processed in accordance with MIL-STD-883C, but are inherently non-compliant because of package, solderability, or surface treatment exceptions to those specifications. The order number (Valid Combination) is formed by a combination of:

APL Products: A. Device Number
 B. Speed Option (if applicable)
 C. Device Class
 D. Package Type
 E. Lead Finish

CPL Products: A. Device Number
 B. Speed Option (if applicable)
 C. Package Type
 D. Temparature Range
 E. CPL Status

APL Products

AM29203   /B   X   C

E. LEAD FINISH
C = Gold

D. PACKAGE TYPE (per 09-000)
X = 48-Pin Sidebrazed Hermetic DIP (SD 048)
Y = 48-Pin Ceramic Topbrazed Flatpack DIP (CFT048)

C. DEVICE CLASS
/B = Class B

B. SPEED OPTION
Not Applicable

A. DEVICE NUMBER/DESCRIPTION
Am29203
Four-Bit Bipolar Microprocessor Slice

CPL Products

AM29203   /L   M   C

E. CPL STATUS
C = CPL Certified

D. TEMPERATURE RANGE
M = Military (−55 to +125°C)

C. PACKAGE TYPE
/L = 52-Pin Ceramic Leadless Chip Carrier (CL 052)

B. SPEED OPTION
Not Applicable

A. DEVICE NUMBER/DESCRIPTION
Am29203
Four-Bit Bipolar Microprocessor Slice

Valid Combinations		
A P L	AM29203	/BXC, /BYC
C P L	AM29203	/LMC

Valid Combinations

Valid Combinations list configurations planned to be supported in volume for this device. Consult the local AMD sales office to confirm availability of specific valid combinations or to check for newly released valid combinations.

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PIN DESCRIPTION

$A_0 - A_3$ RAM A Address Inputs (Input, TTL)
Four RAM address inputs that contain the address of the RAM word appearing at the RAM A output port.

$B_0 - B_3$ RAM B Address Inputs (Input, TTL)
Four RAM address inputs that contain the address of the RAM word appearing at the RAM B output port and into which new data is written when the $\overline{\text{WE}}$ input and the CP input are LOW.

$\overline{\text{WE}}$ Write Enable Input (Input; TTL, Active LOW)
The RAM write enable input. If $\overline{\text{WE}}$ is LOW, data at the Y I/O port is written into the RAM when the CP input is LOW. When $\overline{\text{WE}}$ is HIGH, writing data into the RAM is inhibited.

$DA_0 - DA_3$ External Data Inputs (Input, TTL)
A 4-bit external data input that can be selected as one of the Am29203 ALU operand sources; DA_0 is the least significant bit.

$\overline{\text{EA}}$ Control Input (Input; TTL, Active LOW)
A control input that, when HIGH selects DA_{0-3} as the ALU R operand, and, when LOW, selects RAM output A as the ALU R operand and the DA_{0-3} output data.

$DB_0 - DB_3$ External Data I/O (Input/Output, Three State)
A 4-bit external data input/output. Under control of the $\overline{\text{OE}_B}$ input, RAM output port B can be directly read on these lines, or input data on these lines can be selected as the ALU S operand.

$\overline{\text{OE}_B}$ Control Input (Input; TTL, Active LOW)
A control input that, when LOW, enables RAM output B onto the DB_{0-3} lines and, when HIGH, disables the RAM output B three-state buffers.

C_n Carry-In Input (Input, TTL)
The carry-in input to the Am29203 ALU.

$I_0 - I_8$ Instruction Inputs (Input, TTL)
The nine instruction inputs used to select the Am29203 operation to be performed.

$\overline{\text{IEN}}$ Instruction Enable Input (Input; TTL, Active LOW)
The instruction enable input that, when LOW, allows the Q Register and the Sign Compare flip-flop to be written. When $\overline{\text{IEN}}$ is HIGH, the Q Register and Sign Compare flip-flop are in the hold mode. On the Am29203, $\overline{\text{IEN}}$ also controls $\overline{\text{WRITE}}$.

C_{n+4} Carry-Out Output (Output, TTL)
This output generally indicates the carry-out of the Am29203 ALU. Refer to Table 5 for an exact definition of this pin.

$\overline{\text{G}}/\text{N}$ Carry-Generate Output (Output, TTL)
A multi-purpose pin that indicates the carry generate, $\overline{\text{G}}$, function at the least significant and intermediate slices, and generally indicates the sign, N, of the ALU result at the most significant slice. Refer to Table 5 for an exact definition of this pin.

$\overline{\text{P}}/\text{OVR}$ Carry-Propagate Output (Output, TTL)
A multi-purpose pin that indicates the carry propagate, $\overline{\text{P}}$, function at the least significant and intermediate slices, and indicates the conventional two's complement overflow, OVR, signal at the most significant slice. Refer to Table 5 for an exact definition of this pin.

Z   Open-Collector I/O Pin (Input/Output, Open Collector)
An open-collector I/O pin that, when HIGH, generally indicates the outputs are all LOW. For some Special Functions, Z is used as an input pin. Refer to Table 5 for an exact definition of this pin.

SIO_0, SIO_3 Bidirectional Serial I/O for the ALU (Input/Output, Three State)
Bidirectional serial shift I/O for the ALU shifter. During a shift-up operation, SIO_0 is an input and SIO_3 an output. During a shift-down operation, SIO_3 is an input and SIO_0 is an output. Refer to Tables 3 and 4 for an exact definition of these pins.

QIO_0, QIO_3 Bidirectional Serial-Shift I/O for the Q Shifter (Input/Output, Three State)
Bidirectional serial shift I/O for the Q shifter that operates like SIO_0 and SIO_3. Refer to Tables 3 and 4 for an exact definition of these pins.

$\overline{\text{LSS}}$ Control Input (Input; TTL, Active LOW)
An input pin that, when tied LOW, programs the chip to act as the least significant slice (LSS) of an Am29203 array and enables the $\overline{\text{WRITE}}$ output onto the $\overline{\text{WRITE}}/\overline{\text{MSS}}$ pin. When $\overline{\text{LSS}}$ is tied HIGH, the chip is programmed to operate as either an intermediate or most significant slice and the $\overline{\text{WRITE}}$ output buffer is disabled.

$\overline{\text{WRITE}}/\overline{\text{MSS}}$ Control Input (Input/Output; Three State, Active LOW)
When $\overline{\text{LSS}}$ is tied LOW, the $\overline{\text{WRITE}}$ output signal appears at this pin; the $\overline{\text{WRITE}}$ signal is LOW when an instruction that writes data into the RAM is being executed. When $\overline{\text{LSS}}$ is tied HIGH, $\overline{\text{WRITE}}/\overline{\text{MSS}}$ is an input pin; tying it HIGH programs the chip to operate as an intermediate slice (IS) and tying it LOW programs the chip to operate as the most significant slice (MSS).

$Y_0 - Y_3$ Data I/O (Input/Output, Three State)
Four data inputs/outputs of the Am29203. Under control of the $\overline{\text{OE}_Y}$ input, the ALU shifter output data can be enabled onto these lines, or these lines can be used as data inputs when external data is written directly into the RAM.

$\overline{\text{OE}_Y}$ Control Input (Input, TTL)
A control input that, when LOW, enables the ALU shifter output data onto the Y_{0-3} lines and, when HIGH, disables the Y_{0-3} three-state output buffers.

CP   Clock Input (Input, TTL)
The clock input to the Am29203. The Q Register and Sign Compare flip-flop are clocked on the LOW-to-HIGH transition of the CP signal. When enabled by $\overline{\text{WE}}$, data is written in the RAM when CP is LOW.

FUNCTIONAL DESCRIPTION

Architecture of the Am29203

The Am29203 is a high-performance, cascadable, 4-bit bipolar microprocessor slice designed for use in CPUs, peripheral controllers, microprogrammable machines, and numerous other applications. The microinstruction flexibility of the Am29203 allows the efficient emulation of almost any digital computing machine. The 9-bit microinstruction selects the ALU sources, function and destination. The Am29203 is cascadable with full lookahead or ripple carry, has three-state outputs, and provides various ALU status flag outputs. Advanced Low-Power Schottky processing is used to fabricate this LSI circuit.

All data paths within the device are 4 bits wide. As shown in the block diagram, the device consists of a 16-word by 4-bit, 2-port RAM with latches on both output ports, a high-performance ALU and shifter, a multi-purpose Q Register with shifter input, and a 9-bit instruction decoder.

Two-Port RAM

Any two RAM words addressed at the A and B address ports can be read simultaneously at the respective RAM A and B output ports. Identical data appear at the two output ports when the same address is applied to both address ports. The latches at the RAM output ports are transparent when the clock input, CP, is HIGH and they hold the RAM output data when CP is LOW. Under control of the $\overline{OE_B}$ three-state output enable, RAM data can be read directly at the Am2903 DB I/O port. On the Am29203, $\overline{EA}$ provides the same feature at the DA port.

External data at the Am29203 Y I/O port can be written directly into the RAM, or ALU shifter output data can be enabled onto the Y I/O port and entered into the RAM. Data is written into the RAM at the B address when the write enable input, $\overline{WE}$, is LOW and the clock input, CP, is LOW.

Arithmetic Logic Unit

The Am29203 high-performance ALU can perform seven arithmetic and nine logic operations on two 4-bit operands. Multiplexers at the ALU inputs provide the capability to select various pairs of ALU source operands. The $\overline{EA}$ input selects either the DA external data input or RAM output port A for use as one ALU operand and the $\overline{OE_B}$ and I_0 inputs select RAM output port B, DB external data input, or the Q Register content for use as the second ALU operand. Also, during some ALU operations, zeroes are forced at the ALU operand inputs. Thus, the Am29203 ALU can operate on data from two external sources, from an internal and external source, or from two internal sources. Table 1 shows all possible pairs of ALU source operands as a function of the $\overline{EA}$, $\overline{OE_B}$, and I_0 inputs.

TABLE 1. ALU OPERAND SOURCES

$\overline{EA}$	I_0	$\overline{OE_B}$	ALU Operand R	ALU Operand S
L	L	L	RAM Output A	RAM Output B
L	L	H	RAM Output A	DB_{0-3}
L	H	X	RAM Output A	Q Register
H	L	L	DA_{0-3}	RAM Output B
H	L	H	DA_{0-3}	DB_{0-3}
H	H	X	DA_{0-3}	Q Register

L = LOW
H = HIGH
X = Don't Care

TABLE 2. Am29203 ALU FUNCTIONS

I_4	I_3	I_2	I_1	I_0	ALU Functions
L	L	L	L	L	Special Functions
L	L	L	L	H	F_i = HIGH
L	L	L	H	X	F = S Minus R Minus 1 Plus C_n
L	L	H	L	X	F = R Minus S Minus 1 Plus C_n
L	L	H	H	X	F = R Plus S Plus C_n
L	H	L	L	X	F = S Plus C_n
L	H	L	H	X	F = $\overline{S}$ Plus C_n
L	H	H	L	L	Reserved Special Functions
L	H	H	L	H	F = R Plus C_n
L	H	H	H	L	Reserved Special Functions
L	H	H	H	H	F = $\overline{R}$ Plus C_n
H	L	L	L	L	Special Functions
H	L	L	L	H	F_i = LOW
H	L	L	H	X	F_i = $\overline{R_i}$ AND S_i
H	L	H	L	X	F_i = R_i EXCLUSIVE NOR S_i
H	L	H	H	X	F_i = R_i EXCLUSIVE OR S_i
H	H	L	L	X	F_i = R_i AND S_i
H	H	L	H	X	F_i = R_i NOR S_i
H	H	H	L	X	F_i = R_i NAND S_i
H	H	H	H	X	F_i = R_i OR S_i

L = LOW
H = HIGH
i = 0 to 3
X = LOW or HIGH

When instruction bits I_4, I_3, I_2, I_1, and I_0 are LOW, the Am29203 executes special functions. Table 4 defines these special functions and the operation which the ALU performs for each. When the Am29203 executes instructions other than the 16 special functions, the ALU operation is determined by instruction bits I_4, I_3, I_2, and I_1. Table 2 defines the ALU operation as a function of these four instruction bits.

Am29203s may be cascaded in either a ripple carry or lookahead carry fashion. When a number of Am29203s are cascaded, each slice must be programmed to be a most significant slice (MSS), intermediate slice (IS), or least significant slice (LSS) of the array. The carry-generate, G, and carry-propagate, P, signals required for a lookahead carry scheme are generated by the Am29203 and are available as outputs of the least significant and intermediate slices.

The Am29203 also generates a carry-out signal, C_{n+4}, which is generally available as an output of each slice. Both the carry-in, C_n, and carry-out, C_{n+4}, signals are active HIGH. The ALU generates two other status outputs. These are negative, N, and overflow, OVR. The N output is generally the most significant (sign) bit of the ALU output and can be used to determine positive or negative results. The OVR output indicates that the arithmetic operation being performed exceeds the available two's complement number range. The N and OVR signals are available as outputs of the most significant slice. Thus, the multipurpose $\overline{G}$/N and $\overline{P}$/OVR outputs indicate $\overline{G}$ and $\overline{P}$ at the least significant and intermediate slices, and sign and overflow at the most significant slice. To some extent, the meaning of the C_{n+4}, $\overline{P}$/OVR, and $\overline{G}$/N signals vary with the ALU function being performed. Refer to Table 5 for an exact definition of these four signals as a function of the Am29203 instruction.

ALU Shifter

Under instruction control, the ALU shifter passes the ALU output (F) non-shifted, shifts it up one bit position (2F), or shifts it down one bit position (F/2). Both arithmetic and logical shift operations are possible. An arithmetic shift operation shifts data around the most significant (sign) bit position of the most significant slice, and a logical shift operation shifts data through this bit position (see Figure 1). SIO_0 and SIO_3 are bidirectional serial shift inputs/outputs. During a shift-up operation, SIO_0 is generally a serial shift input and SIO_3 a serial shift output. During a shift-down operation, SIO_3 is generally a serial shift input and SIO_0 a serial shift output.

To some extent, the meaning of the SIO_0 and SIO_3 signals is instruction dependent. Refer to Tables 3 and 4 for an exact definition of these pins.

The ALU shifter also provides the capability to sign extend at slice boundaries. Under instruction control, the SIO_0 (sign) input can be extended through Y_0, Y_1, Y_2, Y_3 and propagated to the SIO_3 output.

A cascadable, 5-bit parity generator/checker is designed into the Am29203 ALU shifter and provides ALU error detection capability. Parity for the F_0, F_1, F_2, F_3 ALU outputs and SIO_3 input is generated and, under instruction control, is made available at the SIO_0 output.

The instruction inputs determine the ALU shifter operation. Table 4 defines the special functions and the operation the ALU shifter performs for each. When the Am29203 executes instructions other than the special functions, the ALU shifter operation is determined by instruction bits I_8, I_7, I_6, I_5. Table 3 defines the ALU shifter operation as a function of these four bits.

Q Register

The Q Register is an auxiliary 4-bit register which is clocked on the LOW-to-HIGH transition of the CP input. It is intended primarily for use in multiplication and division operations; however, it can also be used as an accumulator or holding register for some applications. The ALU output, F, can be loaded into the Q Register and/or the Q Register can be selected as the source for the ALU S operand. The shifter at the input to the Q Register provides the capability to shift the Q Register contents up one bit position (2Q) or down one bit position (Q/2). Only logical shifts are performed. QIO_0 and QIO_3 are bidirectional shift serial inputs/outputs. During a Q Register shift-up operation, QIO_0 is a serial shift input and QIO_3 is a serial shift output. During a shift-down operation, QIO_3 is a serial shift input and QIO_0 is a serial shift output.

Double-length arithmetic and logical shifting capability is provided by the Am29203. The double-length shift is performed by connecting QIO_3 of the most significant slice to SIO_0 of the least significant slice, and executing an instruction which shifts both the ALU output and the Q Register.

The Q Register and shifter are controlled by the instruction inputs. Table 4 defines the Am29203 special functions and the operations which the Q Register and shifter perform for each. When the Am29203 executes instructions other than the special functions, the Q Register and shifter operation is controlled by instruction bits I_8, I_7, I_6, I_5. Table 3 defines the Q Register and shifter operation as a function of these four bits.

DF000780

DF000800
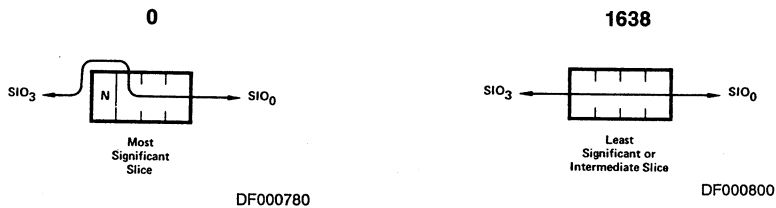
Figure 1-1. Am29203 Arithmetic Shift Path

DF000790
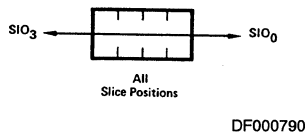
Figure 1-2. Am29203 Logical Shift Path

TABLE 3. ALU DESTINATION CONTROL FOR I_0 OR I_1 OR I_2 OR I_3 = HIGH, $\overline{IEN}$ = LOW

I_8	I_7	I_6	I_5	Hex Code	ALU Shifter Function	SIO_3 Most Sig. Slice	SIO_3 Other Slices	Y_3 Most Sig. Slice	Y_3 Other Slices	Y_2 Most Sig. Slice	Y_2 Other Slices	Y_1	Y_0	SIO_0	$\overline{WRITE}$	Q Reg & Shifter Function	QIO_3	QIO_0
L	L	L	L	0	Arith. F/2→Y	Input	Input	F_3	SIO_3	SIO_3	F_3	F_2	F_1	F_0	L	Hold	Z	Z
L	L	L	H	1	Log. F/2→Y	Input	Input	SIO_3	SIO_3	F_3	F_3	F_2	F_1	F_0	L	Hold	Z	Z
L	L	H	L	2	Arith. F/2→Y	Input	Input	F_3	SIO_3	SIO_3	F_3	F_2	F_1	F_0	L	Log. Q/2→Q	Input	Q_0
L	L	H	H	3	Log. F/2→Y	Input	Input	SIO_3	SIO_3	F_3	F_3	F_2	F_1	F_0	L	Log. Q/2→Q	Input	Q_0
L	H	L	L	4	F→Y	Input	Input	F_3	F_3	F_2	F_2	F_1	F_0	Parity	L	Hold	Z	Z
L	H	L	H	5	F→Y	Input	Input	F_3	F_3	F_2	F_2	F_1	F_0	Parity	H	Log. Q/2→Q	Input	Q_0
L	H	H	L	6	F→Y	Input	Input	F_3	F_3	F_2	F_2	F_1	F_0	Parity	H	F→Q	Z	Z
L	H	H	H	7	F→Y	Input	Input	F_3	F_3	F_2	F_2	F_1	F_0	Parity	L	F→Q	Z	Z
H	L	L	L	8	Arith. 2F→Y	F_2	F_3	F_3	F_2	F_1	F_1	F_0	SIO_0	Input	L	Hold	Z	Z
H	L	L	H	9	Log. 2F→Y	F_3	F_3	F_2	F_2	F_1	F_1	F_0	SIO_0	Input	L	Hold	Z	Z
H	L	H	L	A	Arith. 2F→Y	F_2	F_3	F_3	F_2	F_1	F_1	F_0	SIO_0	Input	L	Log. 2Q→Q	Q_3	Input
H	L	H	H	B	Log. 2F→Y	F_3	F_3	F_2	F_2	F_1	F_1	F_0	SIO_0	Input	L	Log. 2Q→Q	Q_3	Input
H	H	L	L	C	F→Y	F_3	F_3	F_3	F_3	F_2	F_2	F_1	F_0	Z	H	Hold	Z	Z
H	H	L	H	D	F→Y	F_3	F_3	F_3	F_3	F_2	F_2	F_1	F_0	Z	H	Log. 2Q→Q	Q_3	Input
H	H	H	L	E	SIO_0→Y_0, Y_1, Y_2, Y_3	SIO_0	SIO_0	SIO_0	SIO_0	SIO_0	SIO_0	SIO_0	SIO_0	Input	L	Hold	Z	Z
H	H	H	H	F	F→Y	F_3	F_3	F_3	F_3	F_2	F_2	F_1	F_0	Z	L	Hold	Z	Z

Key: Parity = F_3 $\triangledown$ F_2 $\triangledown$ F_1 $\triangledown$ F_0 SIO_3
$\triangledown$ = Exclusive OR
L = LOW
H = HIGH
Z = High Impedance

TABLE 4. SPECIAL FUNCTONS (Note 7)

(Hex) $I_8I_7I_6I_5$	I_4	(Hex) $I_3I_2I_1I_0$	Special Function	ALU Function	ALU Shifter Function	SIO$_3$ Most Sig/ Slice	SIO$_3$ Other Slices	SIO$_0$	Q Reg & Shifter Function	QIO$_3$	QIO$_0$	$\overline{\text{WRITE}}$
0	L	0	Unsigned Multiply	$F = S + C_n$ if $Z = L$ $F = R + S + C_n$ if $Z = H$	Log F/2 → Y (Note 1)	Z	Input	F_0	Log Q/2 → Q	Input	Q_0	L
1	L	0	BCD to Binary Conversion	(Note 4)	Log F/2 → Y	Input	Input	F_0	Log Q/2 → Q	Input	Q_0	L
1	H	0	Multiprecision BCD to Binary	(Note 4)	Log F/2 → Y	Input	Input	F_0	HOLD	Z	Q_0	L
2	L	0	Two's-Complement Multiply	$F = S + C_n$ if $Z = L$ $F = R + S + C_n$ if $Z = H$	Log F/2 → Y (Note 2)	Z	Input	F_0	Log Q/2 → Q	Input	Q_0	L
3	L	0	Decrement by One or Two	$F = S - 2 + C_n$	F → Y	Z	Z	Parity	Hold	Z	Z	L
4	L	0	Increment by One or Two	$F = S + 1 + C_n$	F → Y	Input	Input	Parity	Hold	Z	Z	L
5	L	0	Sign/Magnitude Two's Complement	$F = S + C_n$ if $Z = L$ $F = \overline{S} + C_n$ if $Z = H$	F → Y (Note 3)	Input	Input	Parity	Hold	Z	Z	L
6	L	0	Two's-Complement Multiply, Last Cycle	$F = S + C_n$ if $Z = L$ $F = S - R - 1 + C_n$ if $Z = H$	Log F/2 → Y (Note 2)	Z	Input	F_0	Log Q/2 → Q	Input	Q_0	L
7	L	0	BCD Divide by Two	(Note 4)	F → Y	Z	Z	Parity	Hold	Z	Z	L
8	L	0	Single Length Normalize	$F = S + C_n$	F → Y	F_3	F_3	Z	Log 2Q → Q	Q_3	Input	L
9	L	0	Binary to BCD Conversion	(Note 5)	Log 2F → Y	F_3	F_3	Input	Log 2Q → Q	Q_3	Input	L
9	H	0	Multiprecision Binary to BCD	(Note 5)	Log 2F → Y	F_3	F_3	Input	Hold	Z	Input	L
A	L	0	Double Length Normalize and First Divide Op	$F = S + C_n$	Log 2F → Y	$R_3 \mathbin{\underline{\vee}} F_3$	F_3	Input	Log 2Q → Q	Q_3	Input	L
B	L	0	BCD Add	$F = R + S + C_n$ BCD (Note 6)	F → Y	0	0	Z	Hold	Z	Z	L
C	L	0	Two's-Complement Divide	$F = S + R + C_n$ if $Z = L$ $F = S - R - 1 + C_n$ if $Z = H$	Log 2F → Y	$\overline{R_3} \mathbin{\underline{\vee}} F$	F_3	Input	Log 2Q → Q	Q_3	Input	L
D	L	0	BCD Subtract	$F = R - S - 1 + C_n$ BCD (Note 6)	F → Y	0	0	Z	Hold	Z	Z	L
E	L	0	Two's-Complement Divide Correction and Remainder	$F = S + R + C_n$ if $Z = L$ $F = S - R - 1 + C_n$ if $Z = H$	F → Y	F_3	F_3	Z	Log 2Q → Q	Q_3	Input	L
F	L	0	BCD Subtract	$F = S - R - 1 + C_n$ BCD (Note 6)	F → Y	0	0	Z	Hold	Z	Z	L

Notes: 1. At the most significant slice only, the C_{n+4} signal is internally gated to the Y_3 output.
2. At the most significant slice only, $F_3 \mathbin{\underline{\vee}} OVR$ is internally gated to the Y_3 output.
3. At the most significant slice only, $S_3 \mathbin{\underline{\vee}} F_3$ is generated at the Y_3 output.
4. On each slice, $F = S$ if magnitude of S_{0-3} is less than 8 and $F = S$ minus 3 if magnitude of S_{0-3} is 8 or greater.
5. On each slice, $F = S$ if magnitude of S_{0-3} is less than 5 and $F = S$ plus 3 if magnitude of S_{0-3} is 5 or greater. Addition is module 16.
6. Additions and subtractions are BCD adds and subtracts. Results are undefined if R or S are not in valid BCD format.
7. The Q Register cannot be used explicitly as an operand for any Special Functions. It is defined implicitly within the functions.

Key: L = LOW   Z = High Impedance
H = HIGH $\mathbin{\underline{\vee}}$ = Exclusive OR
X = Don't Care   Parity = $SIO_3 \mathbin{\underline{\vee}} F_3 \mathbin{\underline{\vee}} F_2 \mathbin{\underline{\vee}} F_1 \mathbin{\underline{\vee}} F_0$
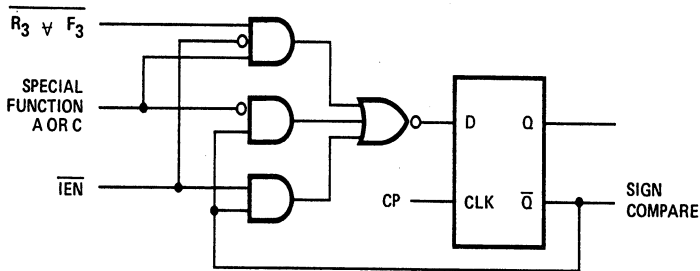
DF000760

Figure 2. Sign Compare Flip-Flop

The sign compare signal appears at the Z output of the most significant slice during special functions C, D and E, F. Refer to Table 5.

Output Buffers

The DB, DA, and Y ports are bidirectional I/O ports driven by three-state output buffers with external output enable controls.

The Y output buffers are enabled when the $\overline{OEY}$ input is LOW and are in the high impedance state when $\overline{OEY}$ is HIGH. The DB output buffers are enabled when the $\overline{OEB}$ input is LOW and the DA buffers are enabled when $\overline{EA}$ is LOW.

The zero, Z, pin is an open collector input/output that can be wire-OR'ed between slices. As an output it can be used as a zero detect status flag and generally indicates that the Y_{0-3} pins are all LOW. To some extent the meaning of this signal varies with the instruction being performed. Refer to Table 5 for an exact definition of this signal as a function of the Am29203 instructions. On the Am29203, the Z pin will be HIGH if $\overline{OEY}$ is HIGH, allowing zero detection on less than the full word.

Instruction Decoder

The Instruction Decoder generates required internal control signals as a function of the nine Instruction inputs, I_{0-8}; the Instruction Enable input, $\overline{IEN}$; the $\overline{LSS}$ input; and the $\overline{WRITE}/\overline{MSS}$ input/output.

The $\overline{WRITE}$ output is LOW when an instruction that writes data into the RAM is being executed. Refer to Tables 3 and 4 for a definition of the $\overline{WRITE}$ output as a function of the Am29203 instruction inputs.

On the Am29203, when $\overline{IEN}$ is HIGH, the Q Register and Sign Compare Flip-Flop contents are preserved. When $\overline{IEN}$ is LOW, the Q Register and Sign Compare Flip-Flop can be written according to the Am29203 instruction. The Sign Compare Flip-Flop is an on-chip flip-flop which is used during an Am29203 divide operation (see Figure 2). On the Am29203, $\overline{IEN}$ controls internal writing, but does not affect $\overline{WRITE}$. The $\overline{IEN}$ signal can then be controlled separately at each chip to facilitate byte operations.

Programming the Am29203 Slice Position

Tying the $\overline{LSS}$ input LOW programs the slice to operate as a least significant slice (LSS) and enables the $\overline{WRITE}$ output signal onto the $\overline{WRITE}/\overline{MSS}$ bidirectional I/O pin. When $\overline{LSS}$ is tied HIGH, the $\overline{WRITE}/\overline{MSS}$ pin becomes an input pin; tying the $\overline{WRITE}/\overline{MSS}$ pin HIGH programs the slice to operate as an intermediate slice (IS) and tying it LOW programs the slice to operate as a most significant slice (MSS). The $\overline{W}/\overline{MSS}$ pin must be tied HIGH through a resistor. $\overline{W}/\overline{MSS}$ and $\overline{LSS}$ should not be connected together.

Am29203 Special Functions

The Am29203 provides sixteen special functions which facilitate the implementation of the following operations:

- Single- and Double-Length Normalization
- Two's-Complement Division
- Unsigned and Two's-Complement Multiplication
- Conversion Between Two's Complement and Sign/Magnitude Representation
- Incrementation and Decrementation by One or Two
- BCD add, subtract, and divide by two.
- Single- and double-precision BCD to Binary and Binary to BCD conversion.

Table 4 defines these special functions.

The Single-Length and Double-Length Normalization functions can be used to adjust a single-precision or double-precision floating point number in order to bring its mantissa within a specified range.

Three special functions which can be used to perform a two's complement, non-restoring divide operation are provided by the Am29203. These functions provide both single- and double-precision divide operations and can be performed in "n" clock cycles, where "n" is the number of bits in the quotient.

The Unsigned Multiply special function and the two Two's-Complement Multiply special functions can be used to multiply two n-bit, unsigned or two's-complement numbers, respectively, in n clock cycles. These functions utilize the conditional add and shift algorithm. During the last cycle of the two's-complement multiplication, a conditional subtraction, rather than addition, is performed because the sign bit of the multiplier carries negative weight.

The Sign/Magnitude-Two's Complement special function can be used to convert number representation systems. A number expressed in Sign/Magnitude representation can be converted to the Two's Complement representation, and vice-versa, in one clock cycle.

The Increment by One or Two special function can be used to increment an unsigned or two's complement number by one or two. This is useful in 16-bit word, byte-addressable machines, where the word addresses are multiples of two.

The BCD arithmetic special functions can be used to add or subtract two BCD numbers and generate a valid BCD result in one microcycle. In addition a BCD divide by two adjust instruction can be used to obtain a valid BCD representation after shifting a number down by one bit.

The BCD/Binary conversion special function instructions facilitate single- and double-precision algorithms to convert from BCD to Binary and from Binary to BCD.

TABLE 5. Am29203 STATUS OUTPUTS

(Hex) $I_8 I_7 I_6 I_5$	(Hex) $I_4 I_3 I_2 I_1$	I_0	G_i (I = 0 to 3)	P_i (I = 0 to 3)	C_{n+4}	$\overline{P}$/OVR Most Sig. Slice	$\overline{P}$/OVR Other Slices	$\overline{G}$/N Most Sig. Slice	$\overline{G}$/N Other Slices	X ($\overline{OEY}$=L) Most Sig. Slice	X ($\overline{OEY}$=L) Intermediate Slice	X ($\overline{OEY}$=L) Least Sig. Slice
X	0	H	0	1	0	0	0	F_3	$\overline{G}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$
X	1	X	$\overline{R_i}\wedge S_i$	$\overline{R_i}\vee S_i$	$G\vee PC_n$	$C_{n+3}\veebar C_{n+4}$	$\overline{P}$	F_3	$\overline{G}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$
X	2	X	$R_i\wedge S_i$	$R_i\vee S_i$	$G\vee PC_n$	$C_{n+3}\veebar C_{n+4}$	$\overline{P}$	F_3	$\overline{G}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$
X	3	X	$R_i\wedge S_i$	$R_i\vee S_i$	$G\vee PC_n$	$C_{n+3}\veebar C_{n+4}$	$\overline{P}$	F_3	$\overline{G}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$
X	4	X	0	S_i	$G\vee PC_n$	$C_{n+3}\veebar C_{n+4}$	$\overline{P}$	F_3	$\overline{G}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$
X	5	X	0	$\overline{S_i}$	$G\vee PC_n$	$C_{n+3}\veebar C_{n+4}$	$\overline{P}$	F_3	$\overline{G}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$
X	6	X	0	R_i	$G\vee PC_n$	$C_{n+3}\veebar C_{n+4}$	$\overline{P}$	F_3	$\overline{G}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$
X	7	X	0	$\overline{R_i}$	$G\vee PC_n$	$C_{n+3}\veebar C_{n+4}$	$\overline{P}$	F_3	$\overline{G}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$
X	8	H	0	1	0	0	0	F_3	$\overline{G}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$
X	9	X	$\overline{R_i}\wedge S_i$	1	0	0	0	F_3	$\overline{G}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$
X	A	X	$R_i\wedge S_i$	$R_i\vee S_i$	0	0	0	F_3	$\overline{G}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$
X	B	X	$\overline{R_i}\wedge S_i$	$\overline{R_i}\vee S_i$	0	0	0	F_3	$\overline{G}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$
X	C	X	$R_i\wedge S_i$	1	0	0	0	F_3	$\overline{G}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$
X	D	X	$\overline{R_i}\wedge \overline{S_i}$	1	0	0	0	F_3	$\overline{G}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$
X	E	X	$R_i\wedge S_i$	1	0	0	0	F_3	$\overline{G}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$
X	F	X	$\overline{R_i}\wedge \overline{S_i}$	1	0	0	0	F_3	$\overline{G}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$
0	0	L	0 if Z = L / $R_i\wedge S_i$ if Z = H	S_i if Z = L / $R_i\vee S_i$ if Z = H	$G\vee PC_n$	$C_{n+3}\veebar C_{n+4}$	$\overline{P}$	F_3	$\overline{G}$	Input	Input	Q_0
1	0	L	0	S_i	$G\vee PC_n$	$C_{n+3}\veebar C_{+4}$	$\overline{P}$	F_3	$\overline{G}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$
1	8	L	0	S_i	0	0	0	F_3	$\overline{G}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$
2	0	L	0 if Z = L / $R_i\wedge S_i$ if Z = H	S_i if Z = L / $R_i\vee S_i$ if Z = H	$G\vee PC_n$	$C_{n+3}\veebar C_{n+4}$	$\overline{P}$	F_3	$\overline{G}$	Input	Input	Q_0
3	0	L	(Note 6)	(Note 7)	$G\vee PC_n$	$C_{n+3}\veebar C_{N+4}$	$\overline{P}$	F_3	$\overline{G}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$
4	0	L	(Note 1)	(Note 2)	$G\vee PC_n$	$C_{n+3}\veebar C_{N+4}$	$\overline{P}$	F_3	$\overline{G}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$
5	0	L	0	S_i if Z = L / $\overline{S_i}$ if Z = H	$G\vee PC_n$	$C_{n+3}\veebar C_{n+4}$	$\overline{P}$	F_3 if Z = L / $F_3\veebar S_3$ if Z = H	$\overline{G}$	S_3	Input	Input
6	0	L	0 if Z = L / $\overline{R_i}\wedge S_i$ if Z = H	S_i if Z = L / $R_i\vee S_i$ if Z = H	$G\vee PC_n$	$C_{n+3}\veebar C_{n+4}$	$\overline{P}$	F_3	$\overline{G}$	Input	Input	Q_0
7	0	L	0	S_i	$G\vee PC_n$	$C_{n+3}\veebar C_{n+4}$	$\overline{P}$	F_3	$\overline{G}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$
8	0	L	0	S_i	(Note 3)	$Q_2\veebar Q_1$	$\overline{P}$	Q_3	$\overline{G}$	$\overline{Q_0}\,\overline{Q_1}\,\overline{Q_2}\,\overline{Q_3}$	$\overline{Q_0}\,\overline{Q_1}\,\overline{Q_2}\,\overline{Q_3}$	$\overline{Q_0}\,\overline{Q_1}\,\overline{Q_2}\,\overline{Q_3}$
9	0	L	0	S_i	$G\vee PC_n$	$C_{n+3}\veebar C_{n+4}$	$\overline{P}$	F_3	$\overline{G}$	$\overline{Q_0}\,\overline{Q_1}\,\overline{Q_2}\,\overline{Q_3}$	$\overline{Q_0}\,\overline{Q_1}\,\overline{Q_2}\,\overline{Q_3}$	$\overline{Q_0}\,\overline{Q_1}\,\overline{Q_2}\,\overline{Q_3}$
9	8	L	0	S_i	0	0	0	F_3	$\overline{G}$	$\overline{Q_0}\,\overline{Q_1}\,\overline{Q_2}\,\overline{Q_3}$	$\overline{Q_0}\,\overline{Q_1}\,\overline{Q_2}\,\overline{Q_3}$	$\overline{Q_0}\,\overline{Q_1}\,\overline{Q_2}\,\overline{Q_3}$
A	0	L	0	S_i	(Note 4)	$F_2\veebar F_1$	$\overline{P}$	F_3	$\overline{G}$	(Note 5)	(Note 5)	(Note 5)
B	0	L	$R_i\wedge S_i$	$R_i\vee S_i$	$G\vee PC_n$	(Note 8)	(Note 8)	(Note 9)	(Note 9)	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$
C	0	L	$R_i\wedge S_i$ if Z = L / $\overline{R_i}\wedge S_i$ if Z = H	$R_i\vee S_i$ if Z = L / $\overline{R_i}\vee S_i$ if Z = H	$G\vee PC_n$	$C_{n+3}\veebar C_{n+4}$	$\overline{P}$	F_3	$\overline{G}$	Sign Compare FF Output	Input	Input
D	0	L	$R_i\wedge \overline{S_i}$	$R_i\vee \overline{S_i}$	$G\vee PC_n$	$C_{n+3}\veebar C_{n+4}$	$\overline{P}$	F_3	$\overline{G}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$
E	0	L	$R_i\wedge S_i$ if Z = L / $\overline{R_i}\wedge S_i$ if Z = H	$R_i\vee S_i$ if Z = L / $\overline{R_i}\vee S_i$ if Z = H	$G\vee PC_n$	$C_{n+3}\veebar C_{n+4}$	$\overline{P}$	F_3	$\overline{G}$	Sign Compare FF Output	Input	Input
F	0	L	$\overline{R_i}\wedge S_i$	$\overline{R_i}\vee S_i$	$G\vee PC_n$	$C_{n+3}\veebar C_{n+4}$	$\overline{P}$	F_3	$\overline{G}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$	$\overline{Y_0}\,\overline{Y_1}\,\overline{Y_2}\,\overline{Y_3}$

Notes:
1. If $\overline{LSS}$ is LOW, $G_0 = S_0$ and $G_{1,2,3} = 0$. If $\overline{LSS}$ is HIGH, $G_{0,1,2,3} = 0$.
2. If $\overline{LSS}$ is LOW, $P_0 = 1$ and $P_{1,2,3} = S_{1,2,3}$. If $\overline{LSS}$ is HIGH, $P_i = S_i$.
3. At the most significant slice, $C_{n+4} = Q_3 \veebar Q_2$. At other slices, $C_{n+4} = G\vee PC_n$.
4. At the most significant slice, $C_{n+4} = F_3 \veebar F_2$. At other slices, $C_{n+4} = G\vee PC_n$.
5. $Z = \overline{Q_0}\,\overline{Q_1}\,\overline{Q_2}\,\overline{Q_3}\,\overline{F_0}\,\overline{F_1}\,\overline{F_2}\,\overline{F_3}$.
6. If $\overline{LSS}$ is LOW, $G_0 = 0$ and $G_{1,2,3} = S_{1,2,3}$. If $\overline{LSS}$ is HIGH, $G_{0,1,2,3} = S_{0,1,2,3}$.
7. If $\overline{LSS}$ is LOW, $P_0 = S_0$ and $P_{1,2,3} = 1$. If $\overline{LSS}$ is HIGH, $P_{0,1,2,3} = 1$.
8. On all slices $\overline{P} = (\overline{P_0} + \overline{P_3})\,(\overline{P_0} + \overline{G_2})\,(\overline{P_0} + \overline{G_1} + \overline{P_2})$.
9. On all slices $\overline{G} = \overline{G_3}\,(\overline{G_0} + \overline{G_1} + \overline{P_2})\,(\overline{G_0} + \overline{G_1})\,(\overline{P_1} + \overline{G_2})\,(\overline{P_3} + \overline{P_1}\cdot\overline{P}_2\cdot\overline{G_0})$.

Key:
L = LOW = 0
H = HIGH = 1
V = OR
∧ = AND
∇ = EXCLUSIVE OR
$P = P_3 P_2 P_1 P_0$
$G = G_3 \vee G_2 P_3\ G_1 P_2 P_3 \vee G_0 P_1 P_2 P_3$
$C_{n+3} = G_2 \vee G_1 P_2 \vee G_0 P_1 P_2 \vee C_n P_0 P_1\,P_2$

ABSOLUTE MAXIMUM RATINGS

Storage Temperature .... −65 to +150°C
Ambient Temperature Under Bias .... −55 to +125°C
Supply Voltage to Ground Potential
   Continuous .... −0.5 V to +7.0 V
DC Voltage Applied to Outputs For
   High Output State .... −0.5 V to +V_{CC} Max.
DC Input Voltage .... −0.5 V to +5.5 V
DC Output Current, Into Outputs .... 30 mA
DC Input Current .... −30 mA to +5.0 mA

Stresses above those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent device failure. Functionality at or above these limits is not implied. Exposure to absolute maximum ratings for extended periods may affect device reliability.

OPERATING RANGES

Commercial (C) Devices
   Ambient Temperature (T_A) .... 0 to +70°C
   Supply Voltage .... +4.75 V to +5.25 V

Military (M) Devices
   Case Temperature (T_C) .... −55 to +125°C
   Supply Voltage .... +4.5 V to +5.5 V

Operating ranges define those limits between which the functionality of the device is guaranteed.

DC CHARACTERISTICS over operating range unless otherwise specified (Cont'd.)

Parameter Symbol	Parameter Description	Test Conditions (Note 1)		Min.	Typ. (Note 2)	Max.	Units
V_{OH}	Output HIGH Voltage	V_{CC} = Min., V_{IN} = V_{IH} or V_{IL}	I_{OH} = −1.6 mA Y_0-Y_3,$\overline{G}$/N	2.4			Volts
			I_{OH} = −800 μA DB_{0-3},$\overline{P}$/OVR SIO_0,SIO_3,QIO_0,QIO_3, $\overline{WRITE}$, C_{n+4}	2.4			
I_{CEX}	Output Leakage Current for Z Output (Note 4)	V_{CC} = Min., V_{OH} = 5.5 V V_{IN} = V_{IH} or V_{IL}				250	μA
V_{OL}	Output LOW Voltage	V_{CC} = Min., V_{IN} = V_{IH} or V_{IL}	Y_0,Y_1,Y_2 Y_3,Z I_{OL} = 20 mA(COM'L) / I_{OL} = 16 mA(MIL)			0.5	Volts
			DB_0,DB_1, DB_2,DB_3 I_{OL} = 12 mA(COM'L) / I_{OL} = 8.0 mA(MIL)			0.5	
			$\overline{G}$/N I_{OL} = 18 mA			0.5	
			$\overline{P}$/OVR I_{OL} = 10 mA			0.5	
			C_{n+4},$\overline{WRITE}$ SIO_3,QIO_0 QIO_3,SIO_0 I_{OL} = 8.0 mA			0.5	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs (Note 6)		2.0			Volts
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs (Note 6)				0.8	Volts
V_I	Input Clamp Voltage	V_{CC} = Min., I_{IN} = −18 mA				−1.5	Volts
I_{IL}	Input LOW Current	V_{CC} = Max., V_{IN} = 0.5 V (Note 4)	C_n			−3.6	mA
			Y_0,Y_1,Y_2,Y_3			−1.13	
			I_0,I_1,I_2,I_3,I_4 DA_0,DA_1,DA_2,DA_3			−0.72	
			SIO_0,SIO_3,QIO_0,$\overline{MSS}$ QIO_3,DB_0,DB_1, DB_2,DB_3			−0.77	
			All other inputs			−0.36	
I_{IH}	Input HIGH Current	V_{CC} = Max., V_{IN} = 2.7 V (Note 4)	C_n			200	μA
			Y_0,Y_1,Y_2,Y_3			110	
			I_0-I_4,DA_0-DA_3			40	
			SIO_0,SIO_3,$\overline{MSS}$ QIO_3,DB_{0-3}, QIO_0			90	
			All other inputs			20	

Parameter Symbol	Parameter Description	Test Conditions (Note 1)			Min.	Typ. (Note 2)	Max.	Units
I_I	Input HIGH Current	V_{CC} = Max., V_{IN} = 5.5 V					1.0	mA
I_{OZH} I_{OZL}	Off State (High-Impedance) Output Current	V_{CC} = Max., (Note 4)	$Y_0 - Y_3$	V_O = 2.4 V			110	μA
				V_O = 0.5 V			−1130	
			DB_{0-3}, QIO_0, QIO_3 SIO_0, SIO_3, $\overline{WRITE}$/$\overline{MSS}$	V_O = 2.4 V			90	
				V_O = 0.5 V			−770	
I_{OS}	Output Short-Circuit Current (Note 3)	V_{CC} = Max. + 0.5 V V_O = 0.5 V			−30		−85	mA
I_{CC}	Power Supply Current (Note 5)	V_{CC} = Max.	COM'L	T_A = 0 to 70°C			350	mA
				T_A = 70°C			291	
			MIL	T_C = −55 to 125°C			395	
				T_C = 125°C			258	

Notes: 1. For conditions shown as Min. or Max., use the appropriate value specified under Operating Ranges for the applicable device type.
2. Typical limits are at V_{CC}=5.0 V, 25°C ambient and maximum loading.
3. Not more than one output should be shorted at a time. Duration of the short-circuit test should not exceed one second.
4. Y_{0-3}, DB_{0-3}, $SIO_{0,3}$, $QIO_{0,3}$, and $\overline{WRITE}$/$\overline{MSS}$ are three-state outputs internally connected to TTL inputs. Z is an open-collector output internally connected to a TTL input. Input characteristics are measured under conditions such that the outputs are in the OFF state.
5. Worse case I_{CC} is at minimum temperature.
6. Three input levels provide zero noise immunity and should only be static tested in a noise-free environment (not functionally tested).

SWITCHING TEST CIRCUITS

TC001430
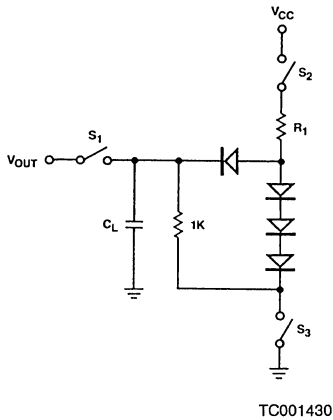
A. Three-State Outputs

TC001380

B. Normal Outputs

TC001420
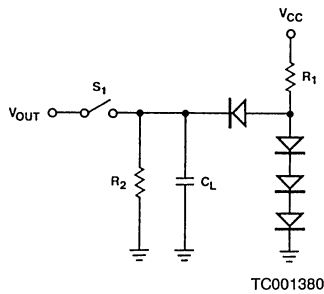
C. Open-Collector Outputs

$$R_2 = \frac{2.4 \text{ V}}{I_{OH}}$$

$$R_1 = \frac{5.0 - V_{BE} - V_{OL}}{\dfrac{I_{OL} + V_{OL}}{1K}}$$

$$R_1 = \frac{5.0 - V_{BE} - V_{OL}}{\dfrac{I_{OL} + V_{OL}}{R_2}}$$
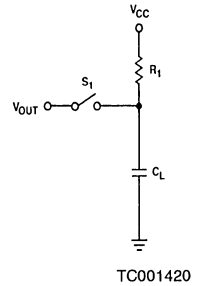
$$R_1 = \frac{5.0 - V_{OL}}{I_{OL}}$$

Notes: 1. $C_L = 50$ pF includes scope probe, wiring and stray capacitances without device in hand in test fixture.
2. S_1, S_2, S_3 are closed during function test and all AC tests except output enable tests.
3. S_1 and S_3 are closed while S_2 is open for t_{PZH} test.
   S_1 and S_2 are closed while S_3 is open for t_{PZL} test.
4. $C_L = 5.0$ pF for output disable tests.

KEY TO SWITCHING WAVEFORMS

WAVEFORM	INPUTS	OUTPUTS
	MUST BE STEADY	WILL BE STEADY
	MAY CHANGE FROM H TO L	WILL BE CHANGING FROM H TO L
	MAY CHANGE FROM L TO H	WILL BE CHANGING FROM L TO H
	DON'T CARE; ANY CHANGE PERMITTED	CHANGING; STATE UNKNOWN
	DOES NOT APPLY	CENTER LINE IS HIGH IMPEDANCE "OFF" STATE

KS000010

TEST OUTPUT LOADS

Test Circuit		R_1 (Ω)	R_2 (kΩ)
A		470	1
A	Y_{0-3}	240	1
B	C_{n+4}	470	3
B	$\overline{P}$/OVR	390	3
B	$\overline{G}$/N	220	1.5
C		270	–

For additional information on testing, see section titled "Guidelines on Testing Am2900 Family Devices," in the 1985 BMLI Data book (Order No. 03851A), page 13-2.

SWITCHING CHARACTERISTICS over operating range unless otherwise specified

The Am29203 switching characteristics are a function of the power supply voltage, the temperature, and the operating mode of the device. The data has been condensed into the following tables:

INDEX TO SWITCHING TABLES

Operating Range (Notes 1 & 2)	Table	Data Type	Applicable To
Commercial	I – A	Clock and Write Pulse	All Functions
Military	II – A		
Commercial	I – B	Enable/Disable Times	All Functions
Military	II – B		
Military	II – C	Setup and Hold Times	All Functions
Commercial	I – 1	Combinational Delays	Standard and Increment/ Decrement by 1 or 2
Military	II – 1		
Commercial	I – 2	Combinational Delays	Multiply Instructions
Military	II – 2		
Commercial	I – 3	Combinational Delays	Divide Instructions
Military	II – 3		
Commercial	I – 4	Combinational Delays	Sign Magnitude to Two's-Complement Conversion
Military	II – 4		
Commercial	I – 5	Combinational Delays	Single Length Normalization
Military	II – 5		
Commercial	I – 6	Combinational Delays	BCD Instructions
Military	II – 6		

Notes: 1. Tables in Section I specify the guaranteed performance of the Am29203 over the commercial operating range of 0 to +70°C, with V_{CC} from 4.75 to 5.25 V. All data are in ns, with inputs switching between 0 and 3 V at 1 V/ns and measurements made at 1.5 V. All outputs have maximum DC load.
2. Tables in Section II specify the guaranteed performance over the military operating range of –55 to +125°C, with V_{CC} from 4.5 to 5.5 V. All data are in ns, with inputs switching between 0 and 3 V at 1 V/ns.

I. Guaranteed Commercial Range Performance

TABLE I-A. CLOCK AND WRITE PULSE CHARACTERISTICS

Minimum Clock LOW Time	30 ns
Minimum Clock HIGH Time	30 ns
Minimum Time CP and $\overline{WE}$ both LOW to Write	15 ns

TABLE I-B. ENABLE/DISABLE TIMES

From	To	Enable	Disable
$\overline{OE_Y}$	Y	25	21
$\overline{OE_B}$	DB	25	21
$\overline{EA}$	DA	25	21
I_8	SIO	25	21
I_8	QIO	38	38
I_{8765}	QIO	38	38
I_{43210}	QIO	38	38
$\overline{LSS}$	$\overline{WR}$	25	21

Note: $C_L = 5$ pF for output disable tests. Measurement is made to a 0.5 V change on the output.

TABLE I-1. STANDARD FUNCTIONS AND INCREMENT BY ONE OR TWO INSTRUCTIONS (SF 4)

From	Y	C_{n+4}	$\overline{G}, \overline{P}$	Z	N	OVR	DB	WRITE/ $\overline{MSS}$	$QIO_{0,3}$	SIO_0	SIO_3	SIO_0 Parity
A, B Addr	67	55	52	74	61	67	28	–	–	41	62	78
DA, DB	58	50	40	65	54	58	–	–	–	35	59	65
Cn	33	18	–	35	28	27	–	–	–	23	30	38
I_{8-0}	64	64	50	72	61	62	–	34	26*	50*	62*	74*
CP	58	42	43	61	54	58	22	–	22	37	54	60
SIO_0, SIO_3	23	–	–	29	–	–	–	–	–	–	29	19
$\overline{MSS}$	44	–	44	44	44	44	–	–	–	44	44	44
Y	–	–	–	17	–	–	–	–	–	–	–	–
$\overline{IEN}$	–	–	–	–	–	–	–	20	–	–	–	–
$\overline{EA}$	58	50	40	65	54	58	–	–	–	35	59	65

Notes: 1. A "–" means the delay path does not exist.
2. An "*" means the output is enabled or disabled by the input. See enable and disable times. A number shown with an "*" is the delay to correct data on an enabled output.

Standard Functions: See Table 2   Increment SF 4: $F = S + 1 + Cn$

TABLE I-2. MULTIPLY INSTRUCTIONS (SF 0, SF 2, SF 6)

From	Slice	Y	C_{n+4}	$\overline{G}, \overline{P}$	Z	N	OVR	DB	WRITE/ $\overline{MSS}$	$QIO_{0,3}$	SIO_0
A, B Addr	MSS	67	(55)	–	–	(61)	(67)	(28)	–	–	(41)
	IS	(67)	(55)	(52)	–	–	–	(28)	–	–	(41)
	LSS	(67)	(55)	(52)	–	–	–	(28)	–	–	(41)
DA, DB	MSS	58	(50)	–	–	(54)	(58)	–	–	–	(35)
	IS	(58)	(50)	(40)	–	–	–	–	–	–	(35)
	LSS	(58)	(50)	(40)	–	–	–	–	–	–	(35)
Cn	MSS	35	(18)	–	–	(28)	(27)	–	–	–	(23)
	IS	(33)	(18)	–	–	–	–	–	–	–	(23)
	LSS	(33)	(18)	–	–	–	–	–	–	–	(23)
I_{8-0}	MSS	94	75	–	–	88	88	–	–	(26)	73*
	IS	94	75	71	–	–	–	–	–	(26)	73*
	LSS	94	75	71	30	–	–	–	(34)	(26)	73*
CP	MSS	58	(42)	–	–	(54)	(58)	(22)	–	(22)	(37)
	IS	(58)	(42)	(43)	–	–	–	(22)	–	(22)	(37)
	LSS	94	75	71	30	–	–	(22)	–	(22)	73
Z	MSS	64	45	–	–	58	58	–	–	–	43
	IS	64	45	41	–	–	–	–	–	–	43
	LSS	–	–	–	–	–	–	–	–	–	–
SIO_0, SIO_3	Any	(23)	–	–	–	–	–	–	–	–	–

Notes: 1. A "–" means the delay path does not exist.
2. An "*" means the output is enabled or disabled by the input. See enable and disable times. A number shown with an "*" is the delay to correct data on an enabled output.
3. A number in parentheses means the delay path is the same as specified in the Standard Functions and Increment by One or Two Instructions Table. This specification is not tested but is guaranteed by correlation to the Standard Function and Increment by One or Two Instruction Test.

Unsigned Multiply

SF 0: $F = S + Cn$ if $Z = 0$
$F = S + R + Cn$ if $Z = 1$
$Y = Log. F/2$
$Q = Log. Q/2$
$Y_3 = C_{n+4}$ (MSS)
$Z = Q_0$ (LSS)

Two's-Complement Multiply

SF 2: $F = S + Cn$ if $Z = 0$
$F = R + S + Cn$ if $Z = 1$
$Y = Log. F/2$
$Q = Log. Q/2$
$Y_3 = F_3 \oplus OVR$ (MSS)
$Z = Q_0$ (LSS)

Two's-Complement Multiply Last Cycle

SF 6: $F = S + Cn$ if $Z = 0$
$F = S - R - 1 + Cn$ if $Z = 1$
$Y = Log. F/2$
$Q = Log. Q/2$
$Y_3 = OVR \oplus$ (MSS)
$Z = Q_0$ (LSS)

TABLE I-3. DIVIDE INSTRUCTIONS (SF A/SF C, SF E)

From	Slice	Y	C_{n+4}	$\overline{G}, \overline{P}$	Z	N	OVR	DB	$\overline{WR}$	$QIO_{0,3}$	SIO_3
					To						
A, B Addr	MSS	(67)	61/(55)	–	74/–	61	67	(28)	–	–	62
	IS	(67)	(55)	(52)	(74)/–	–	–	(28)	–	–	(62)
	LSS	(67)	(55)	(52)	(74)/–	–	–	(28)	–	–	(62)
DA, DB	MSS	(58)	55/(50)	–	65/–	54	58	–	–	–	59
	IS	(58)	(50)	(40)	(65)/–	–	–	–	–	–	(59)
	LSS	(58)	(50)	(40)	(65)/–	–	–	–	–	–	(59)
Cn	MSS	(33)	33/(18)	–	35/–	28	27	–	–	–	32
	IS	(33)	(18)	–	(35)/–	–	–	–·–	–	–	(30)
	LSS	(33)	(18)	–	(35)/–	–	–	–	–	–	(30)
I_{8-0}	MSS	64/84	75/68	–	72/29	61/77	62/77	–	–	(26)	63/83*
	IS	64/84	64/68	50/70	72/–	–	–	–	–	(26)	62/83*
	LSS	64/84	64/68	50/70	72/–	–	–	–	(34)	(26)	62/83*
CP	MSS	(58)/85	46/69	–	61/30	54/66	58/66	(22)	–	(22)	54/79
	IS	(58)	(42)	(43)	(61)/–	–	–	(22)	–	(22)	(54)
	LSS	(58)	(42)	(43)	(61)/–	–	–	(22)	–	(22)	(54)
Z	MSS	–	–	–	–	–	–	–	–	–	–
	IS	–/55	–/39	–/41	–	–	–	–	–	–	–/54
	LSS	–/55	–/39	–/41	–	–	–	–	–	–	–/54
SIO_0, SIO_3	Any	(23)	–	–	–	–	–	–	–	–	–

Notes: 1. A "–" means the delay path does not exist.
2. An "*" means the output is enabled or disabled by the input. See enable and disable times. A number shown with an "*" is the delay to correct data on an enabled output.
3. A number in parentheses means the delay path is the same as specified in the Standard Functions and Increment by One or Two Instructions Table. This specification is not tested but is guaranteed by correlation to the Standard Function and Increment by One or Two Instruction Test.
4. If two delays are given, the first is for 1st divide and normalization; the second is for two's complement divide and two's complement divide correction.

Double Length Normalize and First Divide Op

SF A: $F = S + Cn$
$Y = Log. 2F$
$Q = Log. 2Q$
$SIO_3 = F_3 \oplus R_3$ (MSS)
$C_{n+4} = \overline{F_3} \oplus F_2$ (MSS)
$OVR = F_2 \oplus F_1$ (MSS)
$Z = \overline{Q_0} \ \overline{Q_1} \ \overline{Q_2} \ \overline{Q_3} \ \overline{F_0} \ \overline{F_1} \ \overline{F_2} \ \overline{F_3}$

Two's-Complement Divide

SF C: $F = R + S + Cn$ if $Z = 0$
$F = S - R - 1 + Cn$ if $Z = 1$
$Y = Log. 2F$
$Q = Log. 2Q$
$SIO_3 = \overline{F_3 \oplus R_3}$ (MSS)
$Z = \overline{F_3 \oplus R_3}$ (MSS) from previous cycle

Two's-Complement Divide Correction and Remainder

SF E: $F = R + S + Cn$ if $Z = 0$
$F = S - R - 1 + Cn$ if $Z = 1$
$Y = F$
$Q = Log. 2Q$
$Z = \overline{F_3 \oplus R_3}$ (MSS) from previous cycle

TABLE I-4. SIGN MAGNITUDE TO TWO'S COMPLEMENT CONVERSION (SF 5)

From	Slice	Y	C_{n+4}	$\overline{G}, \overline{P}$	Z	N	OVR	DB	$\overline{\text{WRITE}}/\overline{\text{MSS}}$	$QIO_{0,3}$	SIO_3
A, B Addr	MSS	97	84	–	45	89	89	(28)	–	–	105
	IS	(67)	(55)	(52)	–	–	–	(28)	–	–	(62)
	LSS	(67)	(55)	(52)	–	–	–	(28)	–	–	(62)
DA, DB	MSS	94	79	–	40	84	84	–	–	–	100
	IS	(58)	(50)	(40)	–	–	–	–	–	–	(59)
	LSS	(58)	(50)	(40)	–	–	–	–	–	–	(59)
Cn	MSS	33	(18)	–	–	32	27	–	–	–	(30)
	IS	(33)	(18)	–	–	–	–	–	–	–	(30)
	LSS	(33)	(18)	–	–	–	–	–	–	–	(30)
I_{8-0}	MSS	85	67	–	28	82	73	–	–	(26)	88*
	IS	85	67	63	–	–	–	–	–	(26)	88*
	LSS	85	67	63	–	–	–	–	(34)	(26)	88*
CP	MSS	94	79	–	40	84	84	(22)	–	(22)	100
	IS	(58)	(42)	(43)	–	–	–	(22)	–	(22)	(54)
	LSS	(58)	(42)	(43)	–	–	–	(22)	–	(22)	(54)
Z	MSS	–	–	–	–	–	–	–	–	–	–
	IS	57	39	35	–	–	–	–	–	–	60
	LSS	57	39	35	–	–	–	–	–	–	60
SIO_0, SIO_3	Any	(23)	–	–	–	–	–	–	–	–	–

Notes: 1. A "–" means the delay path does not exist.
2. An "*" means the output is enabled or disabled by the input. See enable and disable times. A number shown with an "*" is the delay to correct data on an enabled output.
3. A number in parentheses means the delay path is the same as specified in the Standard Functions and Increment by One or Two Instructions Table. This specification is not tested but is guaranteed by correlation to the Standard Function and Increment by One or Two Instruction Test.

SF 5: $F = S + C_n$ if $Z = 0$ $Y_3 = S_3 \oplus F_3$ (MSS) $Q = Q$
$F = \overline{S} + C_n$ if $Z = 1$ $Z = S_3$ (MSS) $N = F_3$ if $Z = 0$
   $N = F_3 \oplus S_3$ if $Z = 1$

TABLE I-5. SINGLE LENGTH NORMALIZATION (SF 8)

From	Slice	Y	C_{n+4}	$\overline{G}, \overline{P}$	Z	N	OVR	DB	$\overline{\text{WRITE}}/\overline{\text{MSS}}$	$QIO_{0,3}$	SIO_3
A, B Addr	MSS	(67)	–	–	–	–	–	(28)	–	–	(62)
	IS	(67)	(55)	(52)	–	–	–	(28)	–	–	(62)
	LSS	(67)	(55)	(52)	–	–	–	(28)	–	–	(62)
DA, DB	MSS	(58)	–	–	–	–	–	–	–	–	(59)
	IS	(58)	(50)	(40)	–	–	–	–	–	–	(59)
	LSS	(58)	(50)	(40)	–	–	–	–	–	–	(59)
Cn	MSS	(33)	–	–	–	–	–	–	–	–	(59)
	IS	(33)	(18)	–	–	–	–	–	–	–	(30)
	LSS	(33)	(18)	–	–	–	–	–	–	–	(30)
I_{8-0}	MSS	64	37	–	29	24	24	–	–	(26)	62*
	IS	64	64	50	29	–	–	–	–	(26)	62*
	LSS	64	64	50	29	–	–	–	(34)	(26)	62*
CP	MSS	(58)	29	–	30	26	29	(22)	–	(22)	(54)
	IS	(58)	(42)	(43)	30	–	–	(22)	–	(22)	(54)
	LSS	(58)	(42)	(43)	30	–	–	(22)	–	(22)	(54)
Z	MSS	–	–	–	–	–	–	–	–	–	–
	IS	–	–	–	–	–	–	–	–	–	–
	LSS	–	–	–	–	–	–	–	–	–	–
SIO_0, SIO_3	Any	(23)	–	–	–	–	–	–	–	–	–

Notes: 1. A "–" means the delay path does not exist.
2. An "*" means the output is enabled or disabled by the input. See enable and disable times. A number shown with an "*" is the delay to correct data on an enabled output.
3. A number in parentheses means the delay path is the same as specified in the Standard Functions and Increment by One or Two Instructions Table. This specification is not tested but is guaranteed by correlation to the Standard Function and Increment by One or Two Instruction Test.

SF 8: $F = S + C_n$ $C_{n+4} = Q_3 \oplus Q_2$ (MSS) $OVR = Q_2 \oplus Q_1$ (MSS)
$N = Q_3$ (MSS) $Z = \overline{Q}_0\,\overline{Q}_1\,\overline{Q}_2\,\overline{Q}_3$
$Y = F$
$Q = \text{Log. } 2Q$

TABLE I-6. BCD INSTRUCTIONS (SF 1, SF 7, SF 9, SF B, SF D, SF F)

From	Slice	Y	C_{n+4}	$\overline{G}, \overline{P}$	Z	N	OVR	DA DB	$\overline{WR}$	QIO	SIO_0	SIO_3	SIO Parity
	MSS	72	60	–	74	68	68	28	–	–	55	62	78
A, B Addr	IS	72	60	55	74	–	–	28	–	–	55	62	78
	LSS	72	60	55	74	–	–	28	–	–	55	62	78
	MSS	61	52	–	65	59	59	–	–	–	45	59	65
DA, DB	IS	61	52	48	65	–	–	–	–	–	45	59	65
	LSS	61	52	48	65	–	–	–	–	–	45	59	65
	MSS	36	23	–	37	33	33	–	–	–	30	36	44
C_n	IS	36	23	–	37	–	–	–	–	–	30	36	44
	LSS	36	23	–	37	–	–	–	–	–	30	36	44
	MSS	72	64	–	72/45[1]	62	62	–	–	26	50	62	74
I_{8-0}	IS	72	64	63	72/45[1]	–	–	–	–	26	50	62	74
	LSS	72	64	63	72/45[1]	–	–	–	–	26	50	62	74
	MSS	62	53	–	68/30[1]	62	62	22	–	22	39	60	65
CK	IS	62	53	50	68/30[1]	–	–	22	–	22	39	60	65
	LSS	62	53	50	68/30[1]	–	–	22	–	21	39	60	65
	MSS	–	–	–	–	–	–	–	–	–	–	–	–
Z	IS	–	–	–	–	–	–	–	–	–	–	–	–
	LSS	–	–	–	–	–	–	–	–	–	–	–	–
$\overline{IEN}$	Any	–	–	–	–	–	–	–	–	–	–	–	–
SIO_{0-3}	Any	23	–	–	–	–	–	–	–	–	–	–	–

Note 1: Binary to BCD and multiprecision Binary to BCD Instructions only.

BCD to Binary conversion (SF 1)
BCD divide by two (SF 7)

Binary to BCD conversion (SF 9)
BCD add (SF B)

BCD substract (SF D, SF F)

II. Guaranteed Military Range Performance

TABLE II-A. CLOCK AND WRITE PULSE CHARACTERISTICS

Minimum Clock Low Time	30 ns
Minimum Clock High Time	30 ns
Minimum Time CP and WE both Low to Write	30 ns

TABLE II-B. ENABLE/DISABLE TIMES

From	To	Enable	Disable
$\overline{OE}_Y$	Y	25	21
$\overline{OE}_B$	DB	25	21
$\overline{OE}_A$	DA	25	21
I_8	SIO	25	21
I_8	QIO	38	38
I_{8765}	QIO	38	38
I_{43210}	QIO	38	35
$\overline{LSS}$	$\overline{WR}$	30	25

Note: $C_L = 5.0$ pF for output disable tests. Measurement is made to a 0.5 V change on the output.

TABLE II-C. SETUP AND HOLD TIMES

		HIGH-to-LOW		LOW-to-HIGH		
			Tpwl			
From	With Respect to	Setup	Hold	Setup	Hold	Comments
Y	CP	Don't Care	Don't Care	14	3	Store Y in RAM/Q (Note 1)
$\overline{WE}$ HIGH	CP	15	Tpwl		0	Prevent Writing
$\overline{WE}$ LOW	CP	Don't Care	Don't Care	15	0	Write into RAM
A, B Source	CP	20	3	Don't Care	Don't Care	Latch Data from RAM Out
B Destination	CP	6	Tpwl		3	Write Data into B Address
$QIO_{0,3}$	CP	Don't Care	Don't Care	17	3	Shift Q
I_{8765}	CP	12	–	20	0	Write into Q (Note 2)
$\overline{IEN}$ HIGH	CP	24			0	Prevent Writing into Q
$\overline{IEN}$ LOW	CP	Don't Care	Don't Care	21	0	Write into Q
I_{43210}	CP	18	–	32	0	Write into Q (Note 2)

Notes:
1. The internal Y-bus to RAM setup condition will be met 5 ns after valid Y output ($\overline{OE}_Y = 0$).
2. The setup time with respect to CP falling edge is to prevent writing. The setup time with respect to CP rising edge is to enable writing.
3. For all other setup conditions not specified in this table, the setup time should be the delay to stable Y output, plus the Y to RAM internal setup time. Even if the RAM is not being loaded, this setup condition ensures valid writing into the Q register and sign compare flip-flop.
4. $\overline{WE}$ controls writing into the RAM. $\overline{IEN}$ controls writing into Q and, indirectly, controls $\overline{WE}$ through the $\overline{WRITE}/MSS$ output. To prevent writing, $\overline{IEN}$ and $\overline{WE}$ must go HIGH during the entire clock LOW time. They may go LOW after the clock has gone LOW to cause a write, provided the $\overline{WE}$ LOW and $\overline{IEN}$ LOW setup times are met. Having gone LOW, they should not be returned HIGH until after the clock has gone HIGH.
5. A and B addresses must be set up prior to the clock HIGH-to-LOW transition to latch data at the RAM output.
6. Writing occurs when CP and $\overline{WE}$ are both LOW. The B address should be stable during this entire period.
7. Because I_{8765} controls the writing or not writing of data into RAM and Q, they should be stable during the entire clock LOW time unless $\overline{IEN}$ is HIGH, which prevents writing.
8. The setup time prior to the clock LOW-to-HIGH transition occurs in parallel with the setup time prior to the clock HIGH-to-LOW transition and the clock LOW time. The actual setup time requirement on I_{43210} relative to the clock LOW-to-HIGH transition is the longer of (1) the setup time prior to clock L →H and (2) the sum of the setup time prior to clock H →L and the clock LOW time.

TABLE II-1. STANDARD FUNCTIONS AND INCREMENT BY ONE OR TWO INSTRUCTIONS (SF 4)

From	To											
	Y	C_{n+4}	$\overline{G}, \overline{P}$	Z	N	OVR	DB	$\overline{\text{WRITE}}/\overline{\text{MSS}}$	$QIO_{0,3}$	SIO_0	SIO_3	SIO_0 Parity
A, B Addr	70	58	52	78	68	67	28	–	–	47	71	84
DA, DB	60	52	40	66	55	58	–	–	–	35	61	74
Cn	35	19	–	41	31	29	–	–	–	23	33	40
I_{8-0}	72	69	56	80	71	69	–	36	26*	58*	75*	89*
CP	60	42	43	67	55	58	22	–	22	41	61	66
SIO_0, SIO_3	26	–	–	29	–	–	–	–	–	–	29	19
$\overline{\text{MSS}}$	44	–	44	44	44	44	–	–	–	44	44	44
Y	–	–	–	17	–	–	–	–	–	–	–	–
$\overline{\text{IEN}}$	–	–	–	–	–	–	–	20	–	–	–	–
$\overline{\text{EA}}$	60	52	40	66	55	58	–	–	–	35	61	74

Notes: 1. A "–" means the delay path does not exist.
2. An "*" means the output is enabled or disabled by the input. See enable and disable times. A number shown with an "*" is the delay to correct data on an enabled output.

Standard Functions: See Table 2   Increment SF 4: $F = S + 1 + Cn$

TABLE II-2 MULTIPLY INSTRUCTIONS (SF 0, SF 2, SF 6)

From	Slice	To									
		Y	C_{n+4}	$\overline{G}, \overline{P}$	Z	N	OVR	DB	$\overline{\text{WRITE}}/\overline{\text{MSS}}$	$QIO_{0,3}$	SIO_0
A, B Addr	MSS	72	(58)	–	–	(68)	(67)	(28)	–	–	(47)
	IS	(70)	(58)	(52)	–	–	–	(28)	–	–	(47)
	LSS	(70)	(58)	(52)	–	–	–	(28)	–	–	(47)
DA, DB	MSS	62	(52)	–	–	(55)	(58)	–	–	–	(35)
	IS	(60)	(52)	(40)	–	–	–	–	–	–	(35)
	LSS	(60)	(52)	(40)	–	–	–	–	–	–	(35)
Cn	MSS	40	(19)	–	–	(31)	(29)	–	–	–	(23)
	IS	(35)	(19)	–	–	–	–	–	–	–	(23)
	LSS	(35)	(19)	–	–	–	–	–	–	–	(23)
I_{8-0}	MSS	108	84	–	–	98	98	–	–	(26)	81*
	IS	108	84	80	–	–	–	–	–	(26)	81*
	LSS	108	84	80	33	–	–	–	(36)	(26)	81*
CP	MSS	62	(42)	–	–	(55)	(58)	(22)	–	(22)	(41)
	IS	(60)	(42)	(43)	–	–	–	(22)	–	(22)	(41)
	LSS	109	85	79	34	–	–	(22)	–	(22)	82
Z	MSS	75	51	–	–	65	65	–	–	–	48
	IS	75	51	47	–	–	–	–	–	–	48
	LSS	–	–	–	–	–	–	–	–	–	–
SIO_0, SIO_3	Any	(26)	–	–	–	–	–	–	–	–	–

Notes: 1. A "–" means the delay path does not exist.
2. An "*" means the output is enabled or disabled by the input. See enable and disable times. A number shown with an "*" is the delay to correct data on an enabled output.
3. A number in parentheses means the delay path is the same as specified in the Standard Functions and Increment by One or Two Instructions Table. This specification is not tested but is guaranteed by correlation to the Standard Function and Increment by One or Two Instruction Test.

Unsigned Multiply
SF 0: $F = S + Cn$ if $Z = 0$
  $F = S + R + Cn$ if $Z = 1$
  $Y_3 = C_{n+4}$ (MSS)
  $Z = Q_0$ (LSS)
  $Y = $ Log. $F/2$
  $Q = $ Log. $Q/2$

Two's-Complement Multiply
SF 2: $F = S + Cn$ if $Z = 0$
  $F = R + S + Cn$ if $Z = 1$
  $Y_3 = F_3 \oplus OVR$ (MSS)
  $Z = Q_0$ (LSS)
  $Y = $ Log. $F/2$
  $Q = $ Log. $Q/2$

Two's-Complement Multiply Last Cycle
SF 6: $F = S + Cn$ if $Z = 0$
  $F = S - R - 1 + Cn$ if $Z = 1$
  $Y_3 = OVR \oplus F_3$ (MSS)
  $Z = Q_0$ (LSS)
  $Y = $ Log. $F/2$
  $Q = $ Log. $Q/2$

TABLE II-3. DIVIDE INSTRUCTION (SF A/SF C, SF E)

From	Slice	Y	C_{n+4}	$\overline{G}, \overline{P}$	Z	N	OVR	DB	$\overline{WR}$	$QIO_{0,3}$	SIO_3
					To						
A, B Addr	MSS	(70)	72/(58)	–	78/–	68	67	(28)	–	–	71
	IS	(70)	(58)	(52)	(78)/–	–	–	(28)	–	–	(71)
	LSS	(70)	(58)	(52)	(78)/–	–	–	(28)	–	–	(71)
DA, DB	MSS	(60)	66/(52)	–	66/–	55	58	–	–	–	61
	IS	(60)	(52)	(40)	(66)/–	–	–	–	–	–	(61)
	LSS	(60)	(52)	(40)	(66)/–	–	–	–	–	–	(61)
Cn	MSS	(35)	37/(19)	–	41/–	31	29	–	–	–	36
	IS	(35)	(19)	–	(41)/–	–	–	–	–	–	(33)
	LSS	(35)	(19)	–	(41)/–	–	–	–	–	–	(33)
I_{8-0}	MSS	72/96	89/79	–	80/33	71/91	69/91	–	–	(26)	76/98
	IS	72/96	69/79	56/79	80/–	–	–	–	–	(26)	75/98
	LSS	72/96	69/79	56/79	80/–	–	–	–	(36)	(26)	75/98
CP	MSS	(60)/97	51/80	–	67/34	55/74	58/74	(22)	–	(22)	61/93
	IS	(60)	(42)	(43)	(67)/–	–	–	(22)	–	(22)	(61)
	LSS	(60)	(42)	(43)	(67)/–	–	–	(22)	–	(22)	(61)
Z	MSS	–	–	–	–	–	–	–	–	–	–
	IS	–/63	–/46	–/46	–	–	–	–	–	–	–/65
	LSS	–/63	–/46	–/46	–	–	–	–	–	–	–/65
SIO_0, SIO_3	Any	(26)	–	–	–	–	–	–	–	–	–

Notes: 1. A "–" means the delay path does not exist.
2. An "*" means the output is enabled or disabled by the input. See enable and disable times. A number shown with an "*" is the delay to correct data on an enabled output.
3. A number in parentheses means the delay path is the same as specified in the Standard Functions and Increment by One or Two Instructions Table. This specification is not tested but is guaranteed by correlation to the Standard Function and Increment by One or Two Instruction Test.
4. If two delays are given, the first is for 1st divide and normalization; the second is for two's complement divide and two's complement divide correction.

Double Length Normalize and First Divide Op

SF A: $F = S + Cn$
$SIO_3 = F_3 \oplus R_3$ (MSS)
$C_{n+4} = F_3 \oplus F_2$ (MSS)
$OVR = F_2 \oplus F_1$ (MSS)
$Z = \overline{Q_0}\ \overline{Q_1}\ \overline{Q_2}\ \overline{Q_3}\ \overline{F_0}\ \overline{F_1}\ \overline{F_2}\ \overline{F_3}$
$Y = $ Log. $2F$
$Q = $ Log. $2Q$

Two's-Complement Divide

SF C: $F = R + S + Cn$ if $Z = 0$
$F = S - R - 1 + Cn$ if $Z = 1$
$Y = $ Log. $2F$
$Q = $ Log. $2Q$
$SIO_3 = \overline{F_3 \oplus R_3}$ (MSS)
$Z = \overline{F_3} \oplus R_3$ (MSS) from previous cycle

Two's-Complement Divide Correction and Remainder

SF E: $F = R + S + Cn$ if $Z = 0$
$F = S - R - 1 + Cn$ if $Z = 1$
$Y = F$
$Q = $ Log. $2Q$
$Z = \overline{F_3} \oplus R_3$ (MSS) from previous cycle

					To						
From	**Slice**	**Y**	C_{n+4}	$\overline{G}, \overline{P}$	**Z**	**N**	**OVR**	**DB**	$\overline{\text{WRITE}/}$ $\overline{\text{MSS}}$	$\text{QIO}_{0,3}$	SIO_3
A, B Addr	MSS	114	98	–	52	106	106	(28)	–	–	128
	IS	(70)	(58)	(52)	–	–	–	(28)	–	–	(71)
	LSS	(70)	(58)	(52)	–	–	–	(28)	–	–	(71)
DA, DB	MSS	108	92	–	46	101	101	–	–	–	112
	IS	(60)	(52)	(40)	–	–	–	–	–	–	(61)
	LSS	(60)	(52)	(40)	–	–	–	–	–	–	(61)
Cn	MSS	36	(19)	–	–	35	29	–	–	–	(33)
	IS	(35)	(19)	–	–	–	–	–	–	–	(33)
	LSS	(35)	(19)	–	–	–	–	–	–	–	(33)
I_{8-0}	MSS	98	79	–	33	97	88	–	–	(26)	109*
	IS	98	79	73	–	–	–	–	–	(26)	109*
	LSS	98	79	73	–	–	–	–	(36)	(26)	109*
CP	MSS	108	92	–	46	101	101	(22)	–	(22)	122
	IS	(60)	(42)	(43)	–	–	–	(22)	–	(22)	(61)
	LSS	(60)	(42)	(43)	–	–	–	(22)	–	(22)	(61)
Z	MSS	–	–	–	–	–	–	–	–	–	–
	IS	65	46	40	–	–	–	–	–	–	76
	LSS	65	46	40	–	–	–	–	–	–	76
$\overline{\text{IEN}}$											
$\text{SIO}_0, \text{SIO}_3$	Any	–	–	–	–	–	–	–	–	–	–

Notes: 1. A "–" means the delay path does not exist.

2. An "*" means the output is enabled or disabled by the input. See enable and disable times. A number shown with an "*" is the delay to correct data on an enabled output.

3. A number in parentheses means the delay path is the same as specified in the Standard Functions and Increment by One or Two Instructions Table. This specification is not tested but is guaranteed by correlation to the Standard Function and Increment by One or Two Instruction Test.

SF 5: $F = S + Cn$ if $Z = 0$ $Y_3 = S_3 \oplus F_3$ (MSS) $Q = Q$

        $F = \overline{S} + Cn$ if $Z = 1$ $Z = S_3$ (MSS) $N = F_3$; $Z = 0$

                               $Y = F$ $N = F_3 \oplus S_3$; $Z = 1$

TABLE II-5. SINGLE LENGTH NORMALIZATION (SF 8)

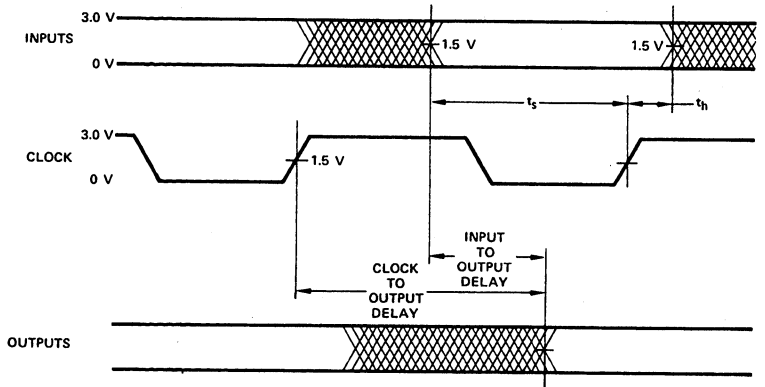| From	Slice	Y	C_{n+4}	$\overline{G},\overline{P}$	Z	N	OVR	DB	WRITE/ $\overline{MSS}$	$QIO_{0,3}$	SIO_3
	MSS	(70)	–	–	–	–	–	(28)	–	–	(71)
A, B Addr	IS	(70)	(58)	(52)	–	–	–	(28)	–	–	(71)
	LSS	(70)	(58)	(52)	–	–	–	(28)	–	–	(71)
	MSS	(60)	–	–	–	–	–	–	–	–	(61)
DA, DB	IS	(60)	(52)	(40)	–	–	–	–	–	–	(61)
	LSS	(60)	(52)	(40)	–	–	–	–	–	–	(61)
	MSS	(35)	–	–	–	–	–	–	–	–	(33)
Cn	IS	(35)	(19)	–	–	–	–	–	–	–	(33)
	LSS	(35)	(19)	–	–	–	–	–	–	–	(33)
	MSS	72	47	–	33	27	27	–	–	(26)	75*
I_{8-0}	IS	72	69	56	33	–	–	–	–	(26)	75*
	LSS	72	69	56	33	–	–	–	–	(26)	75*
	MSS	(60)	31	–	34	26	31	(22)	–	(22)	(61)
CP	IS	(60)	(42)	(43)	34	–	–	(22)	–	(22)	(61)
	LSS	(60)	(42)	(43)	34	–	–	(22)	–	(22)	(61)
	MSS	–	–	–	–	–	–	–	–	–	–
Z	IS	–	–	–	–	–	–	–	–	–	–
	LSS	–	–	–	–	–	–	–	–	–	–
SIO_0, SIO_3	Any	(26)	–	–	–	–	–	–	–	–	–

Notes: 1. A "–" means the delay path does not exist.
2. An "*" means the output is enabled or disabled by the input. See enable and disable times. A number shown with an "*" is the delay to correct data on an enabled output.
3. A number in parentheses means the delay path is the same as specified in the Standard Functions and Increment by One or Two Instructions Table. This specification is not tested but is guaranteed by correlation to the Standard Function and Increment by One or Two Instruction Test.

SF 8: $F = S + Cn$ $C_{n+4} = Q_3 \oplus Q_2$ (MSS) $OVR = Q_2 \oplus Q_1$ (MSS)
$N = Q_3$ (MSS) $Z = \overline{Q_0}\,\overline{Q_1}\,\overline{Q_2}\,\overline{Q_3}$
$Y = F$
$Q = $ Log. 2Q

TABLE II-6. BCD INSTRUCTIONS (SF 1, SF 7, SF 9, SF B, SF D, SF F)

From	Slice	Y	C_{n+4}	$\overline{G},\overline{P}$	Z	N	OVR	DA DB	$\overline{WR}$	QIO	SIO_0	SIO_3	SIO Parity
	MSS	75	65	–	78	70	70	28	–	–	60	71	84
A, B Addr	IS	75	65	57	78	–	–	28	–	–	60	71	84
	LSS	75	65	57	78	–	–	28	–	–	60	71	84
	MSS	62	54	–	70	64	64	–	–	–	50	61	74
DA, DB	IS	62	54	50	70	–	–	–	–	–	50	61	74
	LSS	62	54	50	70	–	–	–	–	–	50	61	74
	MSS	39	26	–	41	37	37	–	–	–	34	39	48
C_n	IS	39	26	–	41	–	–	–	–	–	34	39	48
	LSS	39	26	–	41	–	–	–	–	–	34	39	48
	MSS	76	72	–	80/50[1]	73	73	–	–	26	58	75	89
I_{8-0}	IS	76	72	70	80/50[1]	–	–	–	–	26	58	75	89
	LSS	76	72	70	80/50[1]	–	–	–	–	26	58	75	89
	MSS	67	54	–	70/34[1]	66	66	22	–	22	43	63	74
CK	IS	67	54	52	70/34[1]	–	–	22	–	22	43	63	74
	LSS	67	54	52	70/34[1]	–	–	22	–	22	43	63	74
	MSS	–	–	–	–	–	–	–	–	–	–	–	–
Z	IS	–	–	–	–	–	–	–	–	–	–	–	–
	LSS	–	–	–	–	–	–	–	–	–	–	–	–
$\overline{IEN}$	Any	–	–	–	–	–	–	–	–	–	–	–	–
SIO_{0-3}	Any	23	–	–	–	–	–	–	–	–	–	–	–

Note 1: Binary to BCD and multiprecision Binary to BCD Instructions only.

BCD to Binary conversion (SF 1)   Binary to BCD conversion (SF 9)   BCD subtract (SF D, SF F)
BCD divide by two (SF 7)   BCD add (SF B)

SWITCHING WAVEFORMS

WFR02990

Notes on Test Methods

The following points give the general philosophy that we apply to tests that must be properly engineered if they are to be implemented in an automatic environment. The specifics of what philosophies applied to which test are shown.

1. Ensure the part is adequately decoupled at the test head. Large changes in supply current when the device switches may cause function failures due to V_{CC} changes.

2. Do not leave inputs floating during any tests, as they may oscillate at high frequency.

3. Do not attempt to perform threshold tests at high speed. Following an input transition, ground current may change by as much as 400 mA in 5 – 8 ns. Inductance in the ground cable may allow the ground pin at the device to rise by hundreds of millivolts momentarily.

4. Use extreme care in defining input levels for AC tests. Many inputs may be changed at once, so there will be significant noise at the device pins which may not actually reach V_{IL} or V_{IH} until the noise has settled. AMD recommends using $V_{IL} \leqslant 0$ V and $V_{IH} \geqslant 3$ V for AC tests.

5. To simplify failure analysis, programs should be designed to perform DC, Function, and AC tests as three distinct groups of tests.

6. To assist in testing, AMD offers complete documentation on our test procedures and, in most cases, can provide actual Sentry programs, under license from Sentry.

7. Capacitive Loading for AC Testing

   Automatic testers and their associated hardware have stray capacitance which varies from one type of tester to another, but is generally around 50 pF. This, of course, makes it impossible to make direct measurements of parameters which call for a smaller capacitive load than the associated stray capacitance. Typical examples of this are the so-called "float delays" which measure the propagation delays into and out of the high impedance state and are usually specified at a load capacitance of 5.0 pF. In these cases, the test is peformed at the higher load capacitance (typically 50 pF) and engineering correlations based on data taken with a bench set up are used to predict the result at the lower capacitance.

   Similarly, a product may be specified at more than one capacitive load. Since the typical automatic tester is not capable of switching loads in mid-test, it is impossible to make measurements at both capacitances even though they may both be greater than the stray capacitance. In these cases, a measurement is made at one of the two capacitances. The result at the other capacitance is predicted from engineering correlations based on data taken with a bench set up and the knowledge that certain DC measurements (I_{OH}, I_{OL}, for example) have already been taken and are within specification. In some cases, special DC tests are performed in order to facilitate this correlation.

8. Threshold Testing

   The noise associated with automatic testing, the long, inductive cables, and the high gain of bipolar devices when in the vicinity of the actual device threshold, frequently give rise to oscillations when testing high-speed circuits. These oscillations are not indicative of a reject device, but instead, of an overtaxed test system. To minimize this problem, thresholds are tested at least once for each input pin. Thereafter, "hard" high and low levels are used for other tests. Generally this means that function and AC testing are performed at "hard" input levels rather than at V_{IL} max and V_{IH} min.
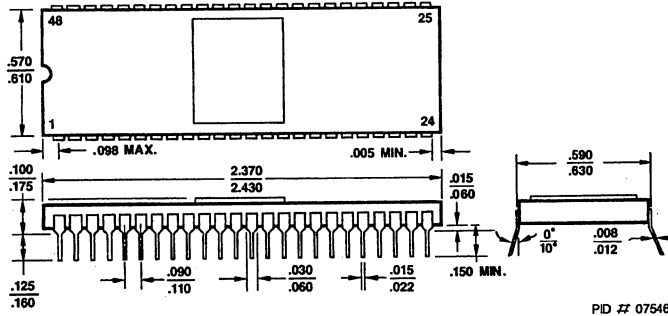
9. AC Testing

   Occasionally, parameters are specified which cannot be measured directly on automatic testers because of tester limitations. Data input hold times often fall into this category. In these cases, the parameter in question is guaranteed by correlating these tests with other AC tests which have been performed. These correlations are arrived at by the cognizant engineer by using data from precise bench measurements in conjunction with the knowledge that certain DC parameters have already been measured and are within specification.
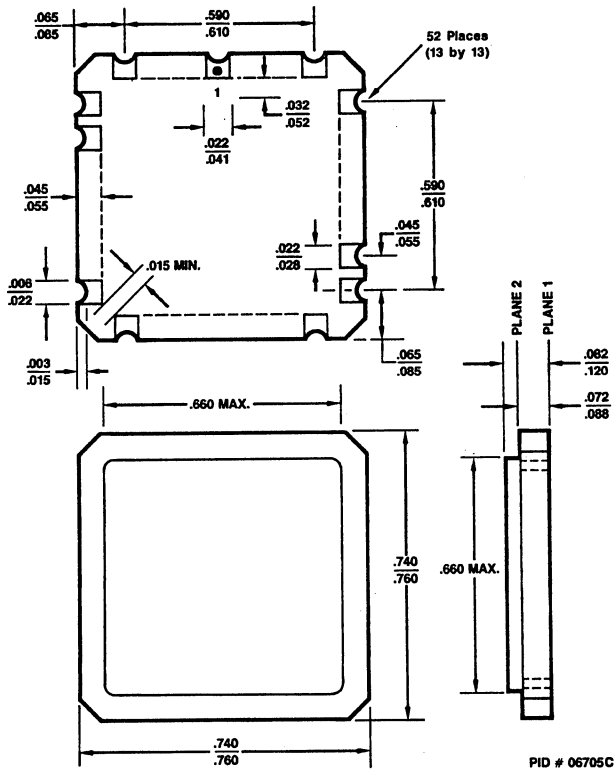
   In some cases, certain AC tests are redundant since they can be shown to be predicted by other tests which have already been performed. In these cases, the redundant tests are not performed.
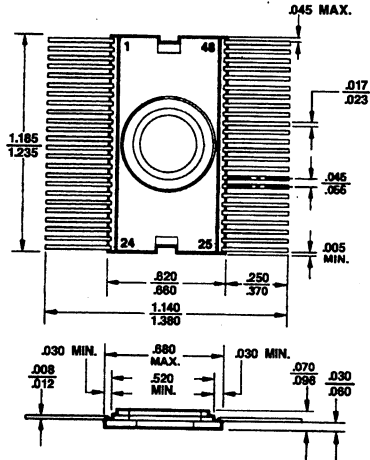
PHYSICAL DIMENSIONS

SD 048

PID # 07546A

CL 052

52 Places
(13 by 13)

PLANE 2

PLANE 1

PID # 06705C

CFT048

PID # 07889A